

→ Diffusion length = finite lifetime τ interval for excess charge carrier before they recombine.

$$L = \sqrt{D \cdot \tau}$$

↳ dis. travelled before diffusing

→ conduction in Intrinsic Semi Cond. -

$$\sigma_p = q n v_p$$

$$\sigma_n = q n v_n$$

$$\left(\frac{V}{I} = R = \frac{1}{\sigma} \right) \quad \left(\frac{V}{I} = R = \frac{1}{q n e A \mu_H} = \frac{1}{q n e A \mu_E} \right) \quad \left(\frac{V}{I} = R = \frac{1}{q n e A \mu} \right)$$

$$\therefore \sigma = q n_i (v_p + v_n)$$

→ Mass Action Law -

- prod. of no. of holes & no. of e^- is const., even after doping
 & is independent of amount of donor & acceptor impurity doping

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→ Carrier concⁿ in Intrinsic Semi-Cond. -

- To calc conductivity, concⁿ of free e^- (n) & concⁿ of free holes (p)

$$\text{So, } dn = N(E) f(E) \cdot dE$$

no. of e^-/m^3 b/w E & $E+dE$.

$$N(E) = \gamma (E - E_c)^{1/2}$$

$$f(E) = \frac{1}{1 + e^{(E - E_F)/RT}} \approx e^{-(E - E_F)/RT}$$

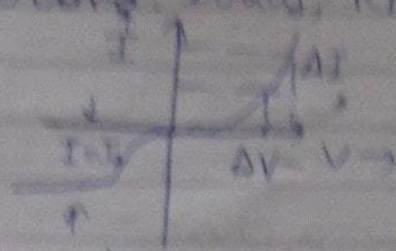
$$n = \int_{E_c}^{\infty} \gamma (E - E_c)^{1/2} e^{-(E - E_F)/RT} dE$$

$$n = N_c e^{-(E_c - E_F)/RT}$$

Diode Current eqⁿ $I = I_s (e^{\frac{V}{V_T}} - 1)$ $V_T = \frac{kT}{q}$ (thermal voltage)
 $V_T = \frac{kT}{q} = \frac{T}{11600}$ (in 300K)
 For one: $I = I_s e^{\frac{V}{V_T}}$ (if $V \gg V_T$), $I = I_s e^{\frac{V}{V_T}}$ (if $V \gg V_T$)
 (if $V \ll V_T$)

Diode Resistance = F.B. cond. only, R.B. resistance

DC Resist (Static) =



$R = \frac{V}{I} = \frac{OA}{OB}$

AC Resist (Dynamic) = $r = \frac{\Delta V}{\Delta I}$ = small change in V / small change in I

Reverse Resist = in several mega Ω

Transition Capacitance = (like in Varactor Diode)

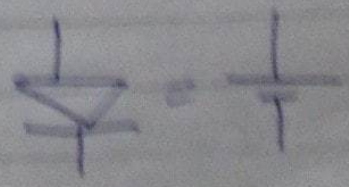
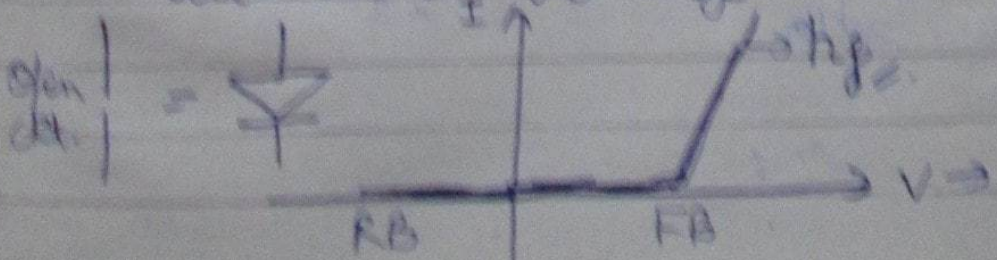
$C_T = \frac{\epsilon A}{W}$ (all layers of depletion region (as 2 sides of jⁿ for "transit" cap)
 - in R.B. only
 - appears in Varactor Diode

Diffusion Capacitance = (C_D)

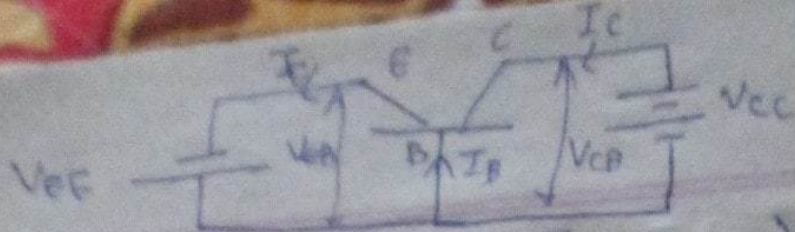
- in F.B. junctⁿ, where $C_D \gg C_T$, - rate of injected charge with applied voltage. $C_D = \frac{dQ}{dV}$; $C_D \propto I_F$ (forward current)

Piecewise Linear Diode Model =

- to get seqⁿ of qes, as VI char is not linear
 - particular seqⁿ of opⁿ of VI diode are broken
 - Approx the actual VI char. by straight line. Resist in series with const^y voltage source.



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Comp to CB,

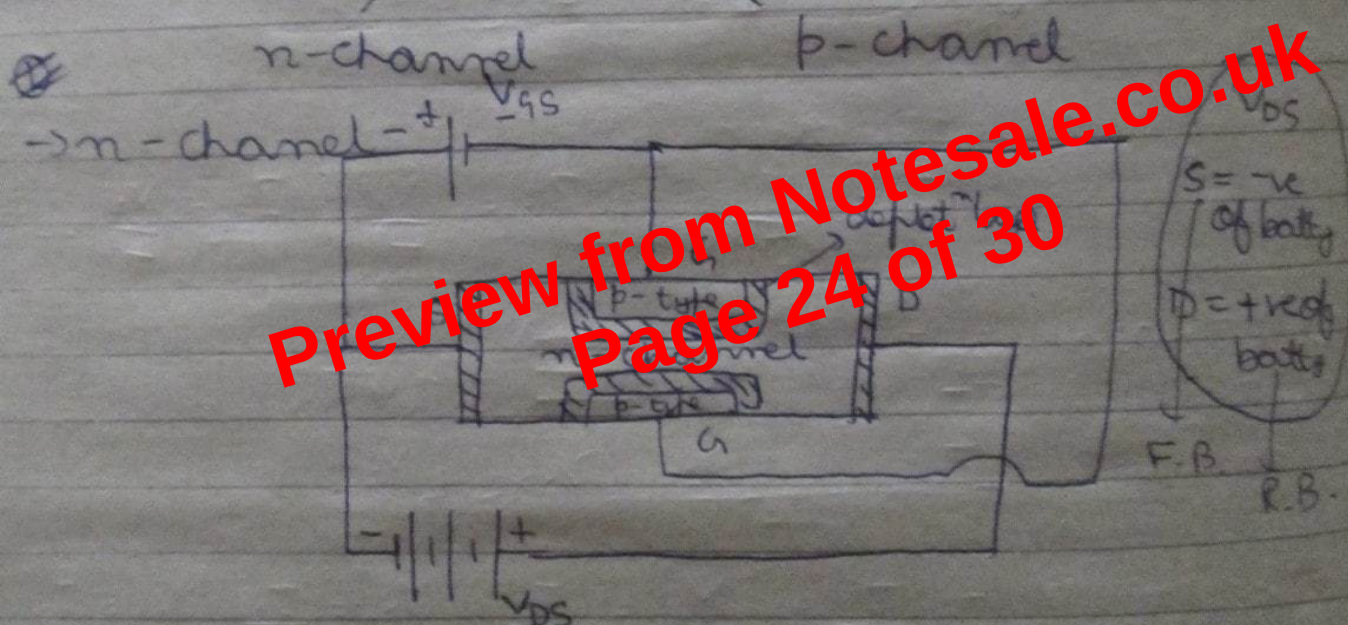
$$V_{EB} = h_i I_E + h_r V_{CB}$$

$$I_C = h_f I_E + h_o V_{CB}$$

$\downarrow I_2$ $\downarrow I_1$ $\downarrow V_2$

→ FET (Field Effect Transistor) -

- flow of current in conductⁿ region is controlled by elec. field.
- condⁿ only by majority carriers.
- Emitter → Source (S); Collector → Drain (D); Base → Gate (G)



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• Operatⁿ -

I. $V_{GS} = V_{DS} = 0 \rightarrow$ thickness of j^n = uniform

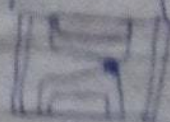
II. $V_{DS} = 0$, $(V_{GS} \downarrow \text{from } 0)$ (R.B. $\uparrow$)
 $\rightarrow$ (off to V_{DS})

$\rightarrow$ PN $j^n \uparrow$, thickness $\uparrow$ until two depletionⁿ layers meet at cut-off V_0

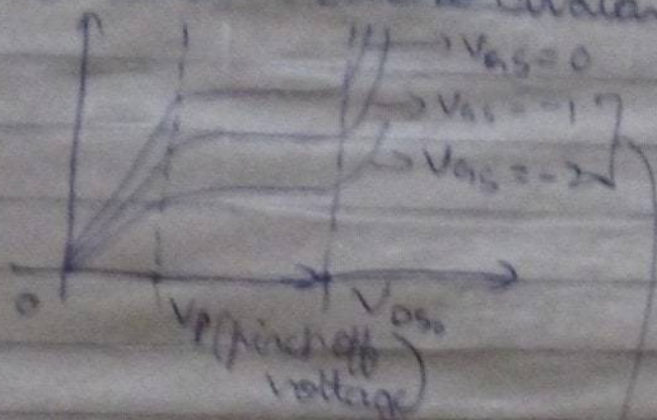
III. $V_{GS} = 0$, $V_{DS} \uparrow$ (F.B. $\uparrow$)

- I_D flow from S to D. $R = \frac{\rho L}{A} \therefore I_D = \frac{V_{DS}}{R}$
 $\rightarrow$ depend on ① A ② V_{DS}
 ③ majority carriers (P). $= \frac{V_{DS} \times A}{\rho \times L}$

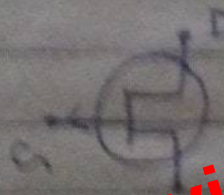
- Reverse voltage across PN_j^{+n} ↑ thickness (wedge shape)
- as $V_{DS} \uparrow$, at certain V_P (pinch off voltage), cross section area = 0



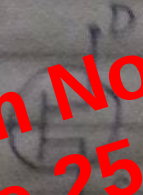
- Characteristics: - as $V_{DS} \uparrow$, $I_D \uparrow$ • $V_{DS} = V_P$ (pinch off)
- At V_{DS} , I_D sudden due to avalanche breakdown



IV. $V_{GS} = -V_P$ (1), $V_{DS} \uparrow \rightarrow$ similar as above.



n-channel



p-channel

⇒ Parameters in JFET:

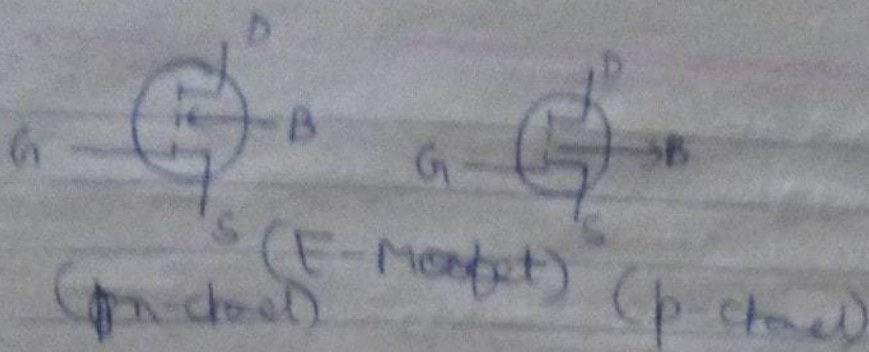
- Drain Resis. $= r_d = \frac{\Delta V_{DS}}{\Delta I_D}$, V_{GS} const

- Transconductance $= \frac{\Delta I_D}{\Delta V_{GS}}$, V_{DS} const.

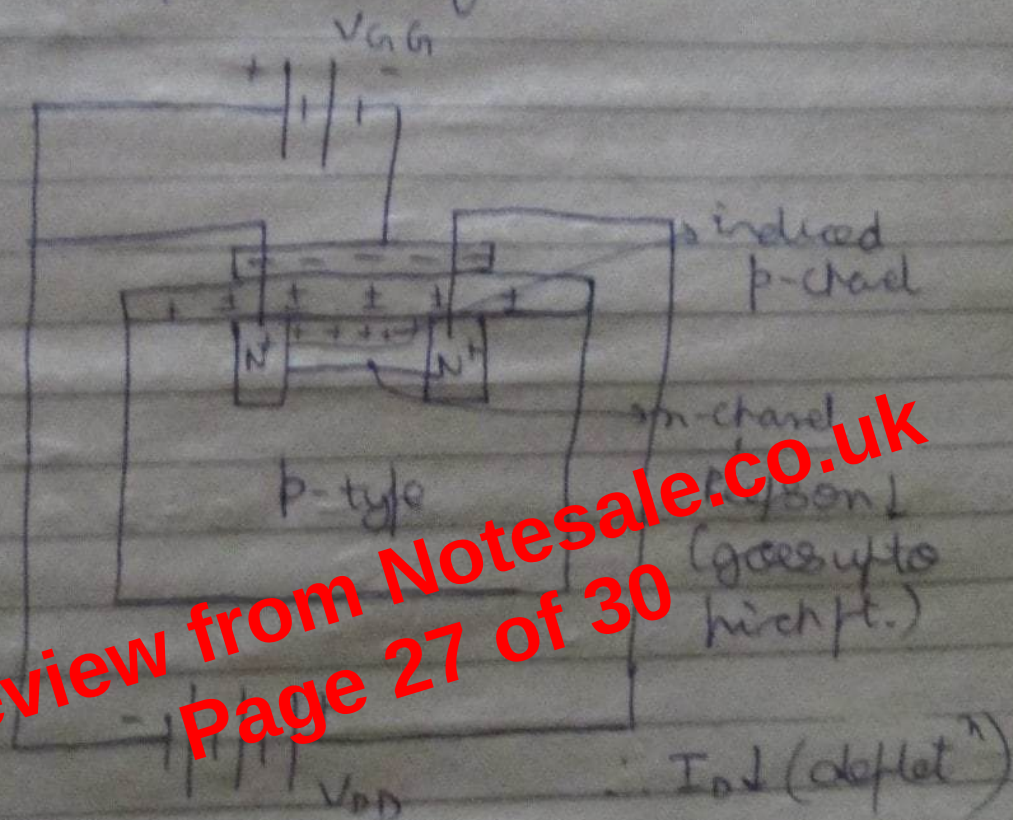
- $\mu = \frac{\Delta V_{DS}}{\Delta V_{GS}}$, I_D const $\mu = g_m \times r_d$

⇒ MOSFET (Metal Oxide Semicond. field effect Transistor)

Gas gate terminal is insulated from channel & is called insulated gate FET.

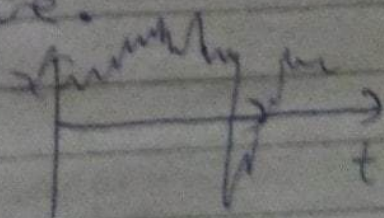


② De-Moorel - (polarities of V_{GS} & V_{DS})



→ Analog Signal - varies with time.

Eg - sine, Eg - temp etc.



→ Digital Signal -

rep. by sequence of no's, each

no rep. by a signal magnitude at a particular

time

generally binary (0 & 1)

